

CRAFT

Circuit Realization At Faster Timescales

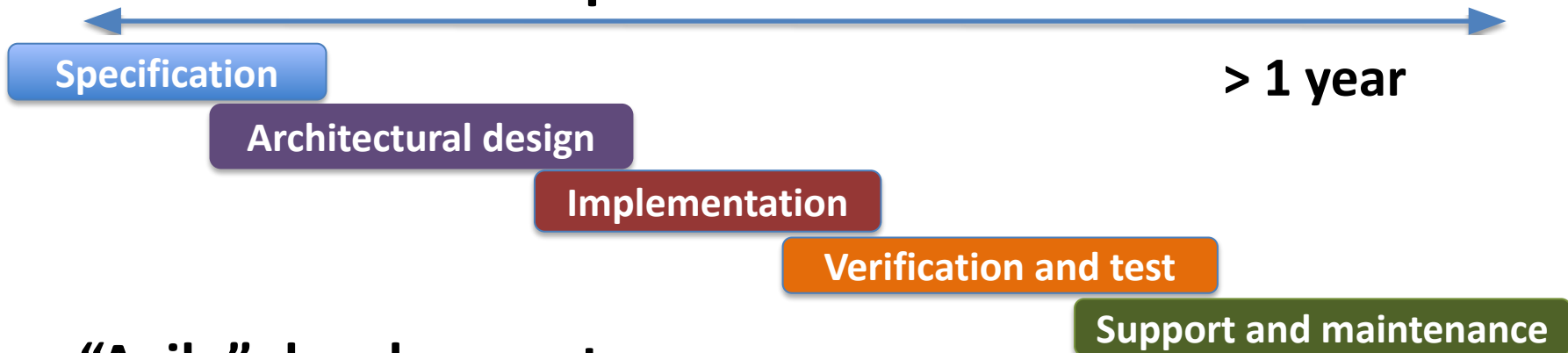
A dark blue diagonal gradient bar that starts from the bottom left corner and extends towards the top right corner, covering the lower half of the slide.

Stevo Bailey and Paul Rigge

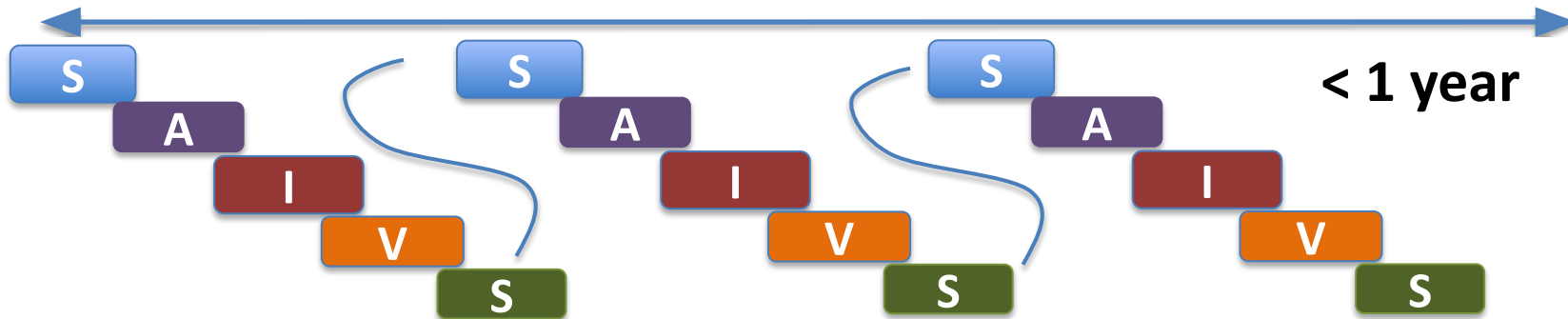
Craft Phase 1 - Agile Development of DSP Chips

Agile Software Design

- “Waterfall” development:



- “Agile” development:

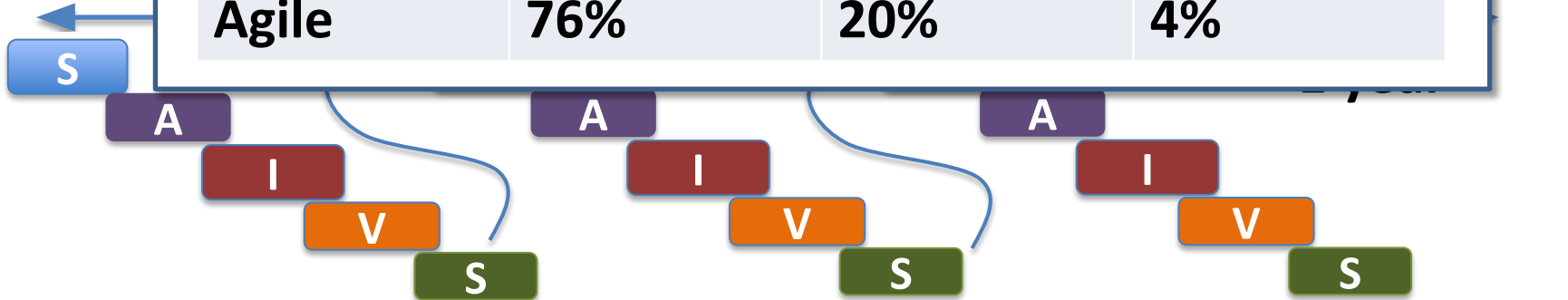


Agile Software Design

- “Waterfall” development:

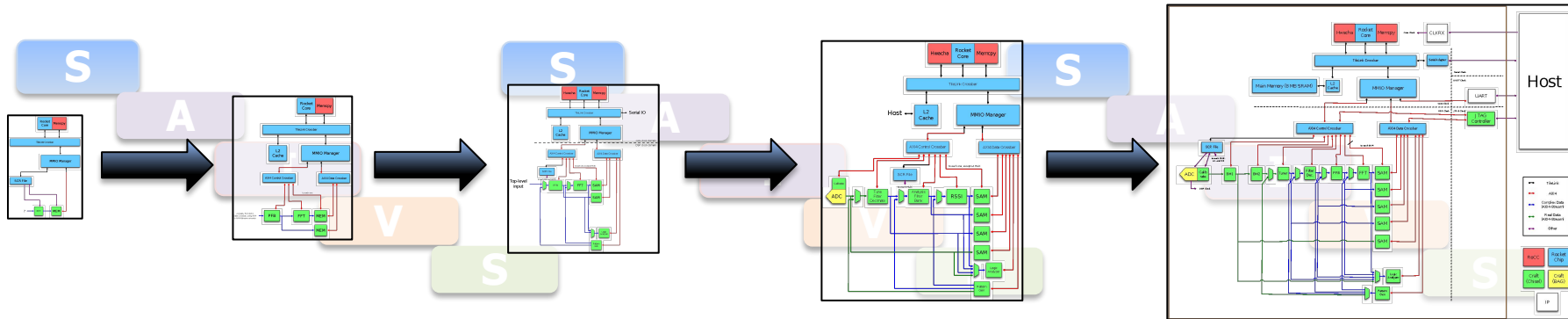


- “Agil



Approach	On-Time	Late	Cancelled
Waterfall	10%	52%	38%
Agile	76%	20%	4%

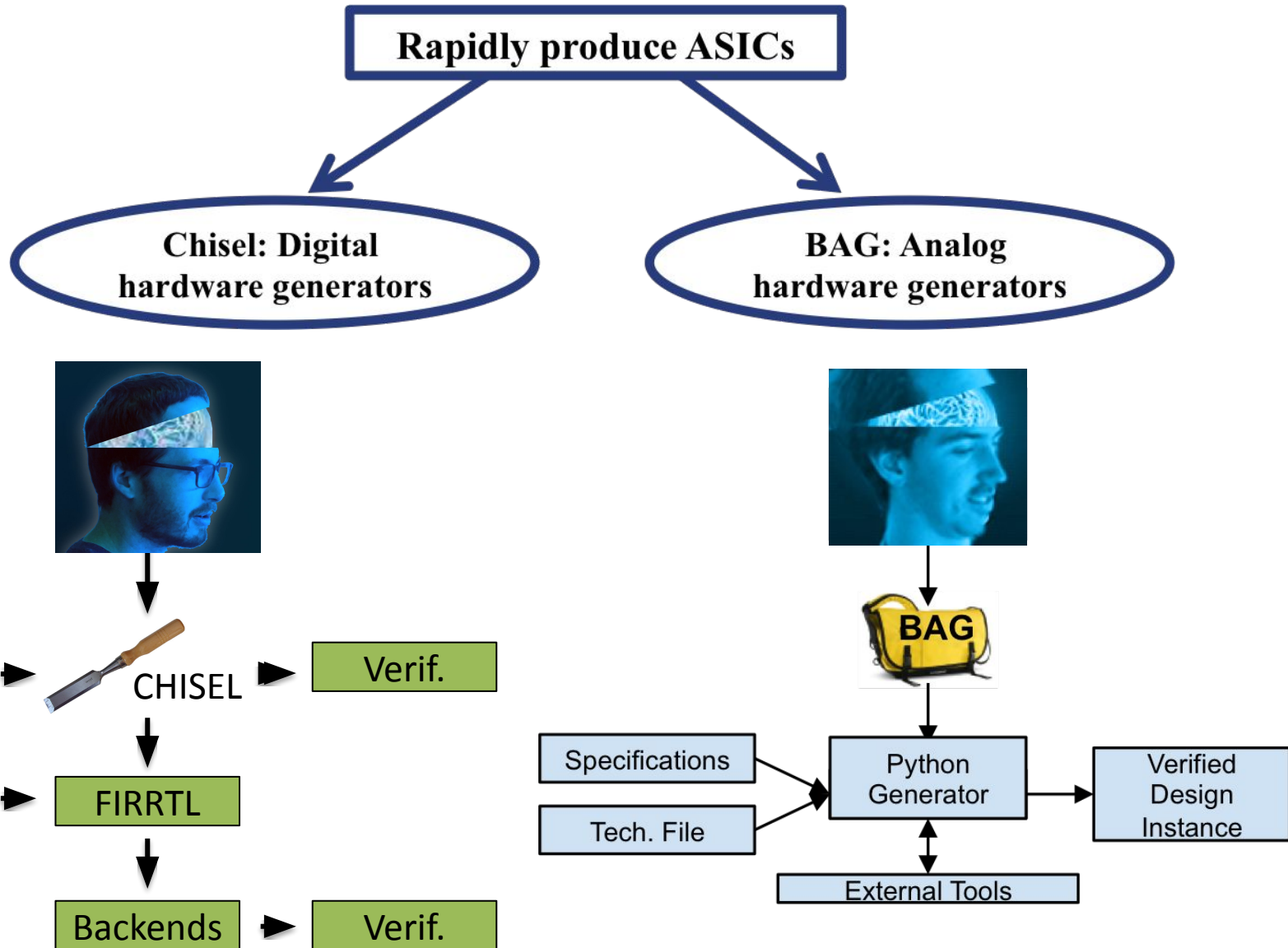
Agile Chip Design



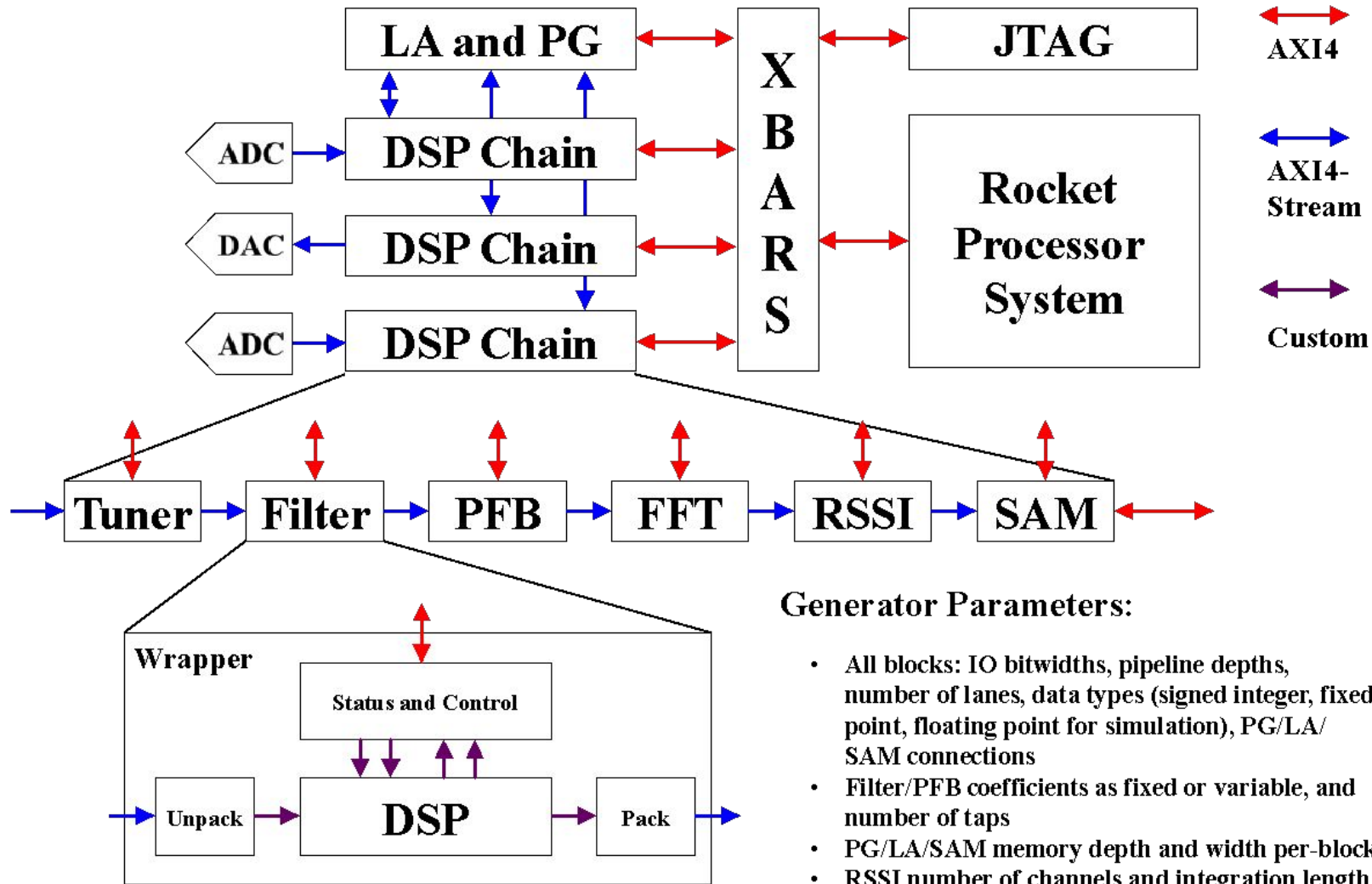
Need methodologies and flows for:

- Scalable, parameterized design generators
- Rapid design turn-around
- Aggressive re-use
- Agile verification and validation

Capturing Design Knowledge



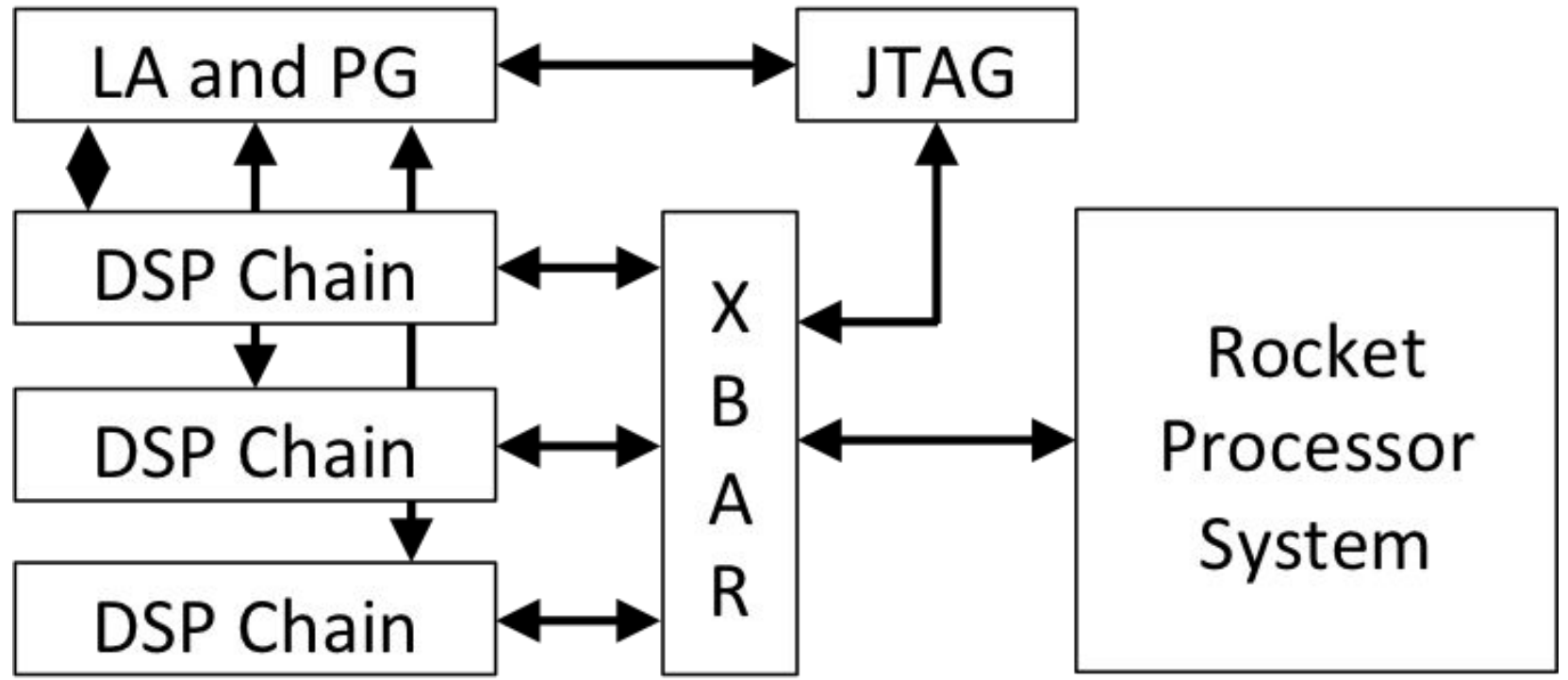
DSP Chip Methodology



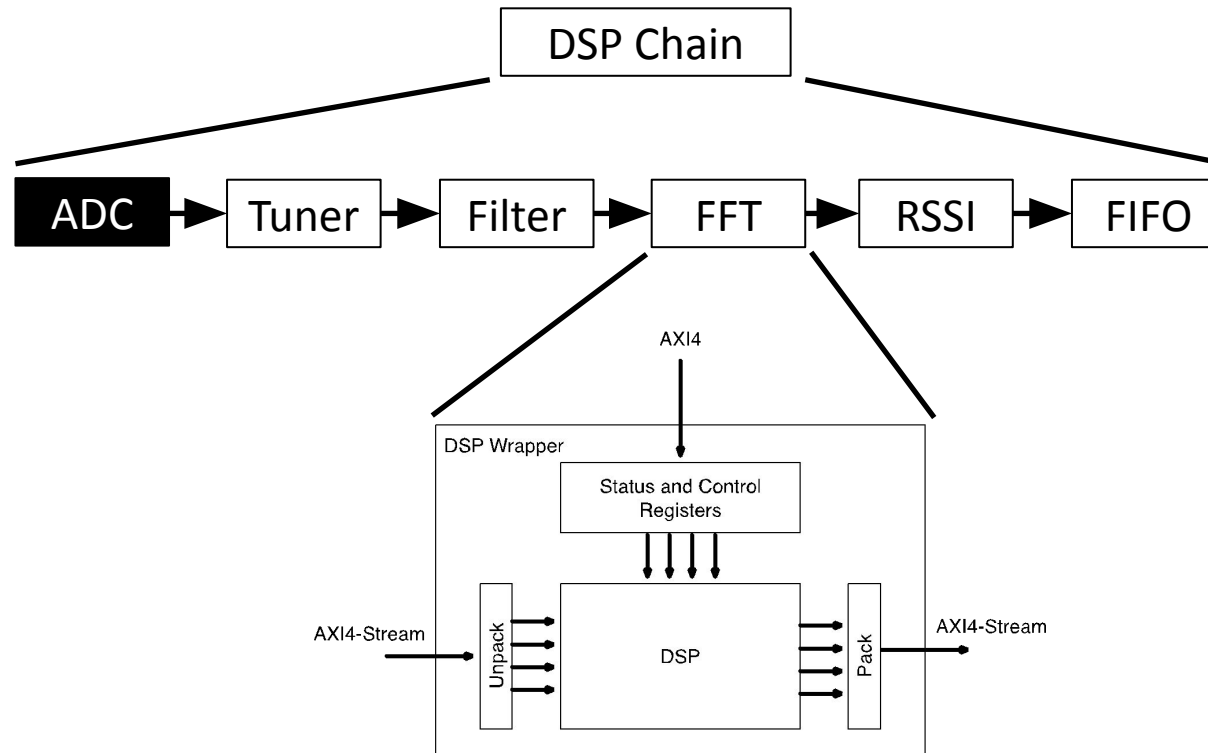
Generator Parameters:

- All blocks: IO bitwidths, pipeline depths, number of lanes, data types (signed integer, fixed point, floating point for simulation), PG/LA/SAM connections
- Filter/PFB coefficients as fixed or variable, and number of taps
- PG/LA/SAM memory depth and width per-block
- RSSI number of channels and integration length
- DSP Chain composition (automatic Xbar sizing)

System Design Methodology



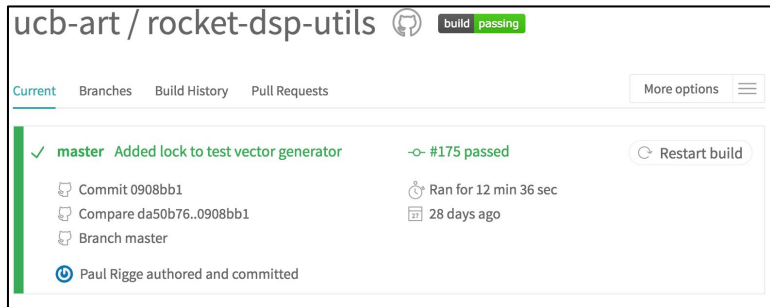
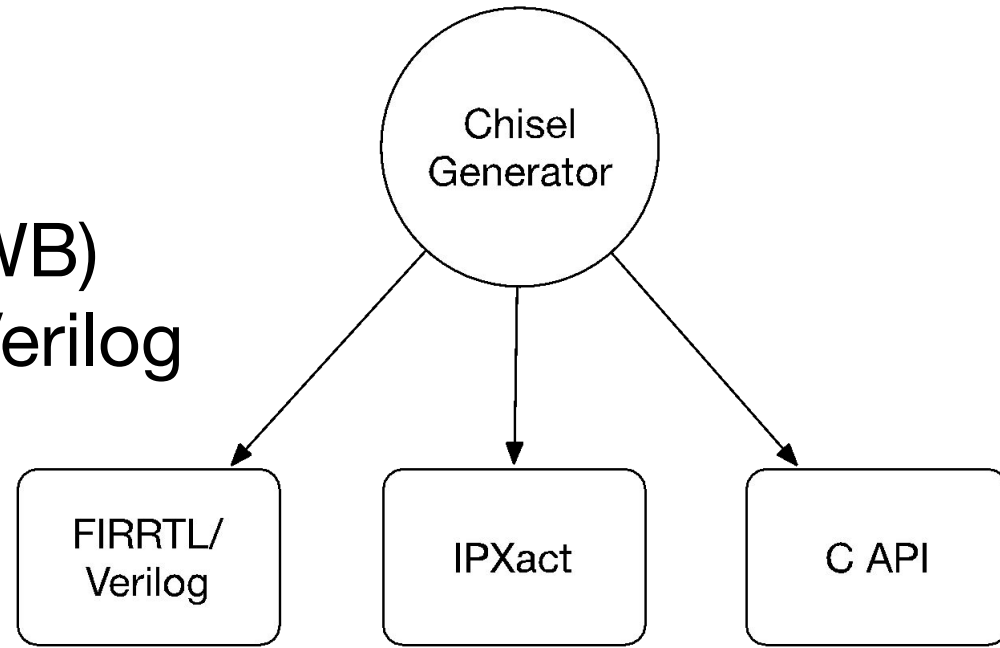
DSP Generators



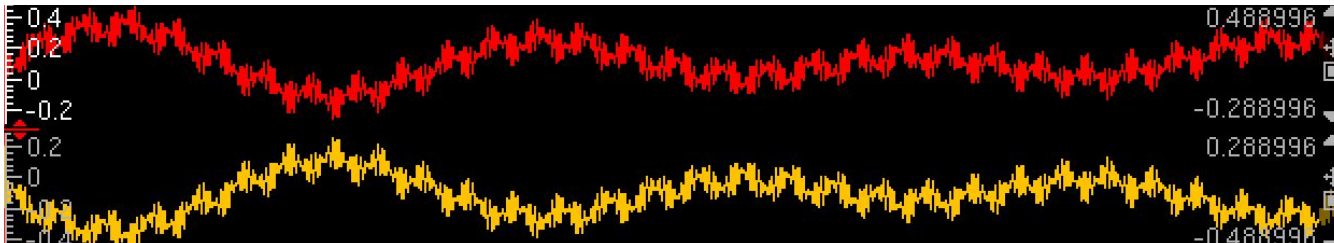
- Programmatic CSR memory interface generation
- IPXact generation for verification
- C header with memory mapping, convenience functions, etc.
- Test harnesses
 - Chisel, Verification Workbench, and C tests!

Verification

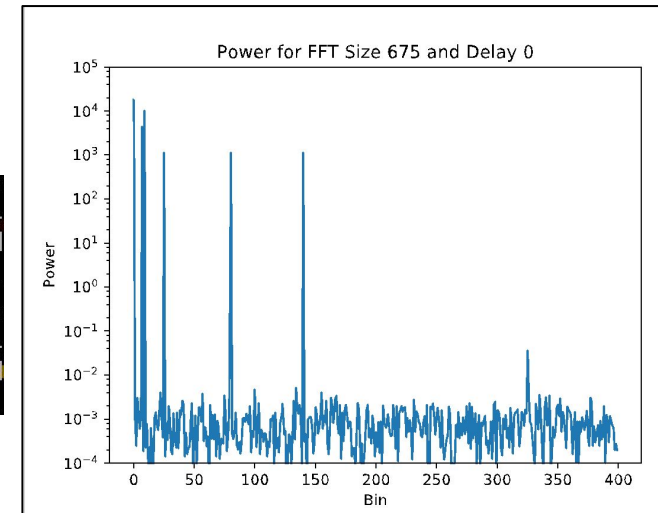
1. Chisel Unit Tests
2. Verification Workbench (VWB)
3. C mixed signal tests with Verilog



Continuous Integration



Top-level C test included SystemVerilog analog model of ADC



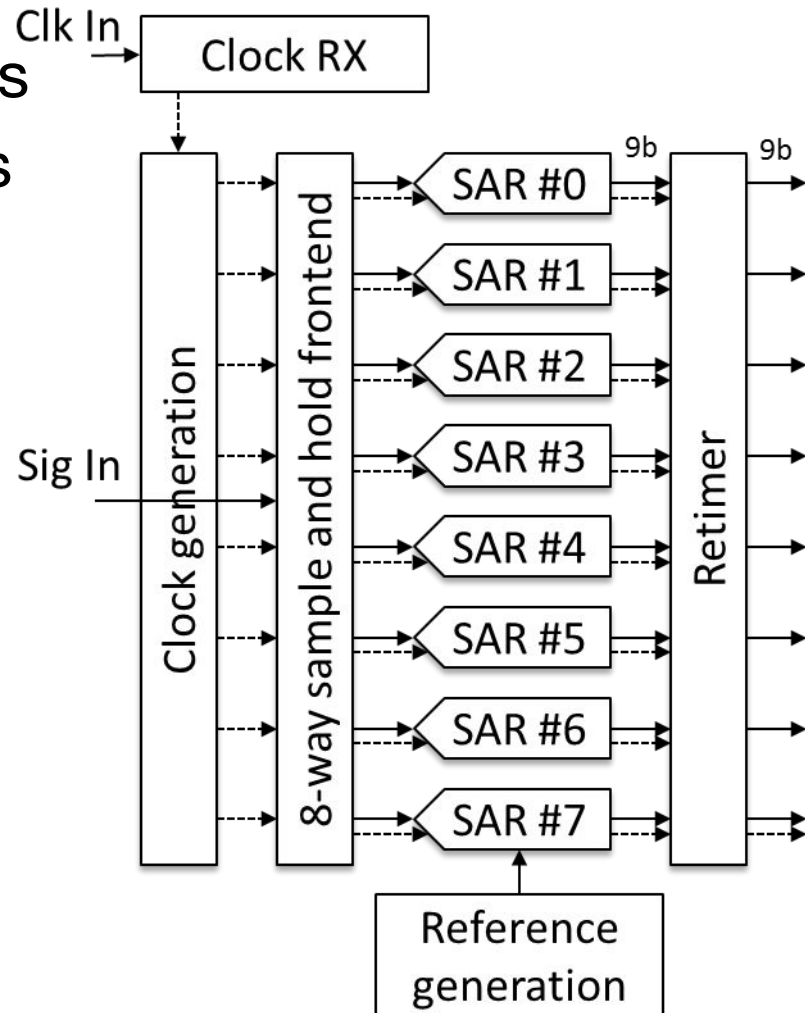
BAG ADC Generator

- **“ADC” generator includes:**

- Asynchronous SAR sub-ADCs
- Resistor-ladder DACs for bias & offset
- High-speed clock RX
- S/H, phase generation circuits with skew correction
- Custom digital retimer

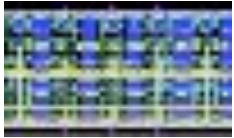
- **Generator parameters:**

- Number of bits, redundancy
- Interleaving factor
- C-DAC thermal noise spec.
- Comparator noise and sample-rate spec.

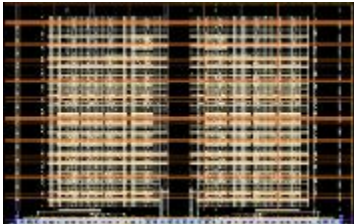


Example Layouts in 16nm

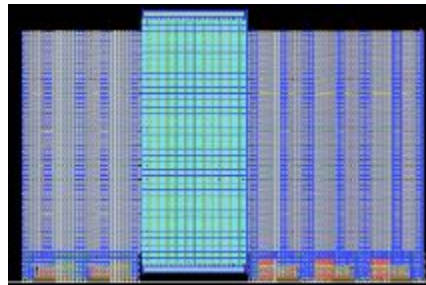
Comparator



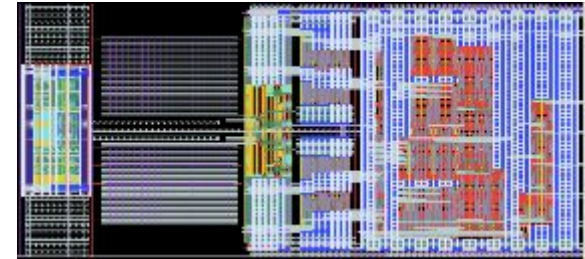
Switch-Cap DAC



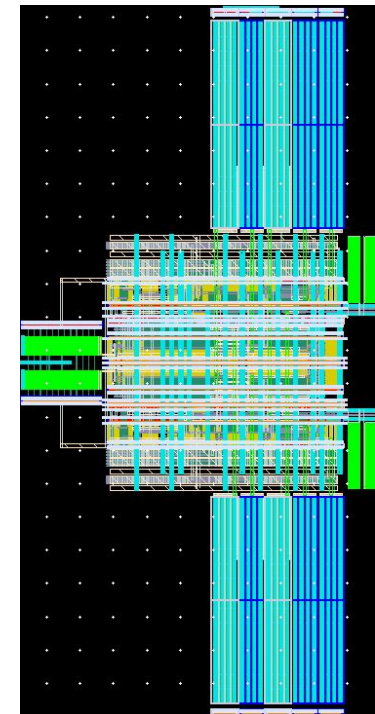
R-ladder DAC



SAR ADC



Time-Interleaved SAR ADC

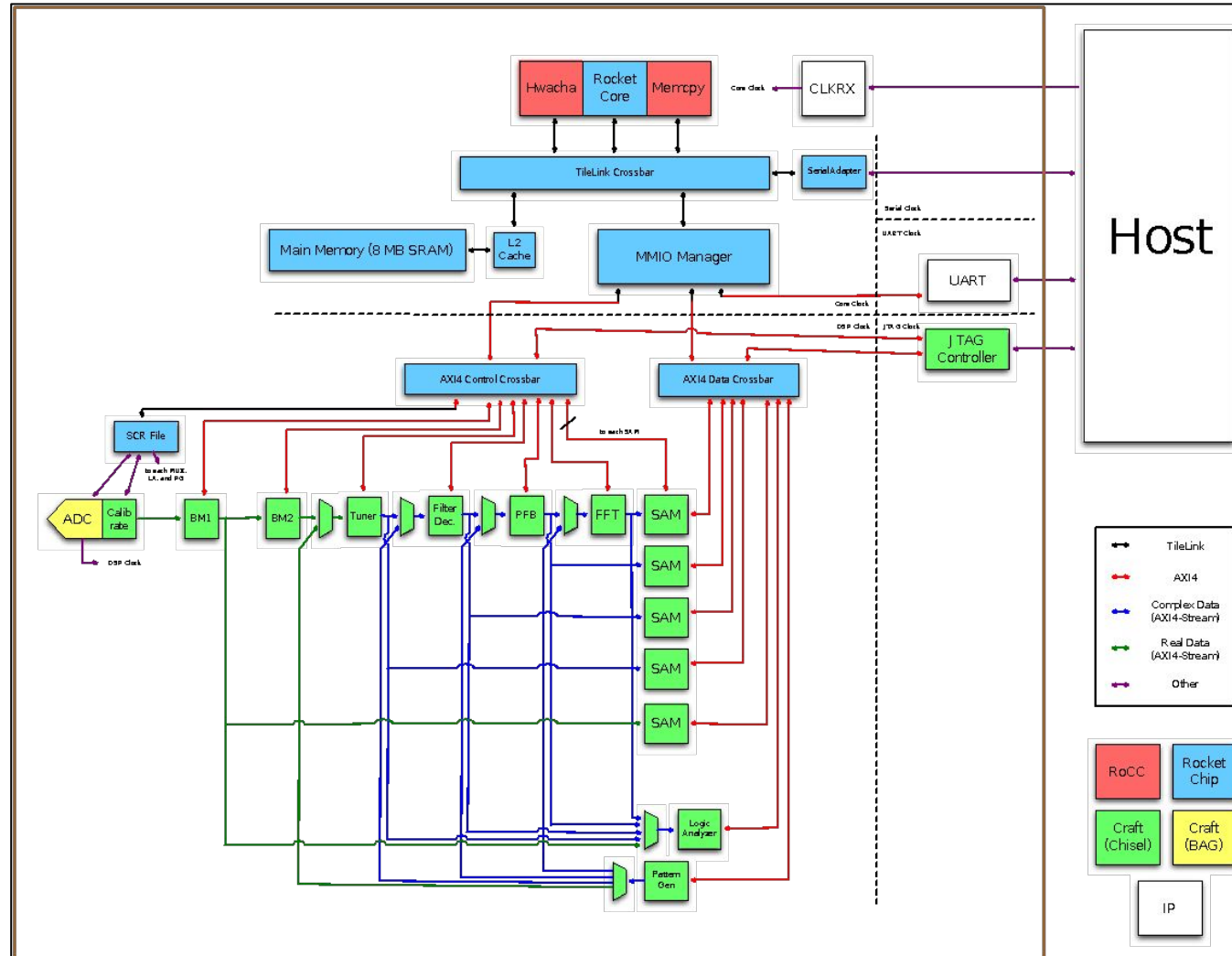


SerDes RX Front-End

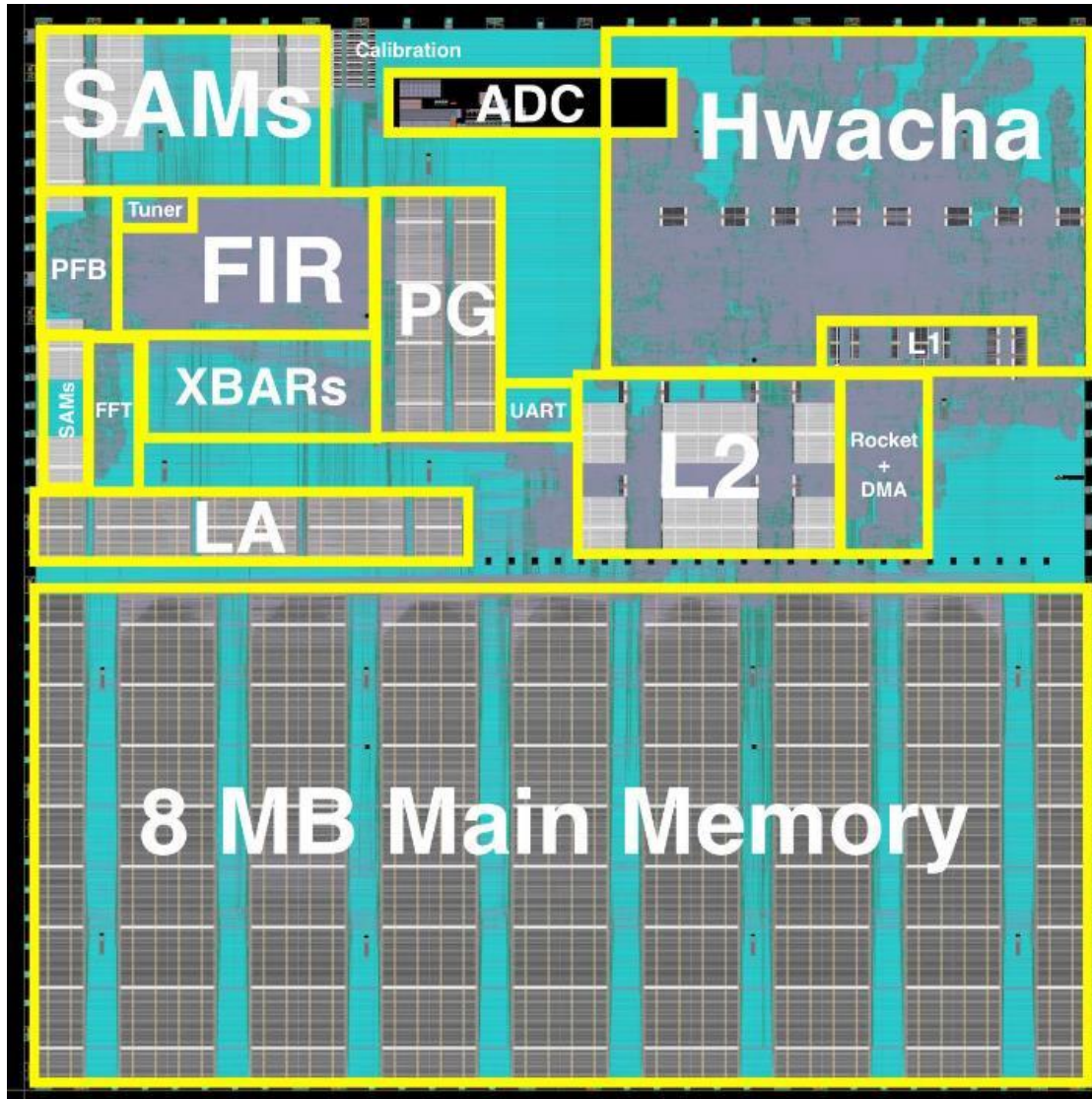
Radar Chip Specs

Chip Highlights:

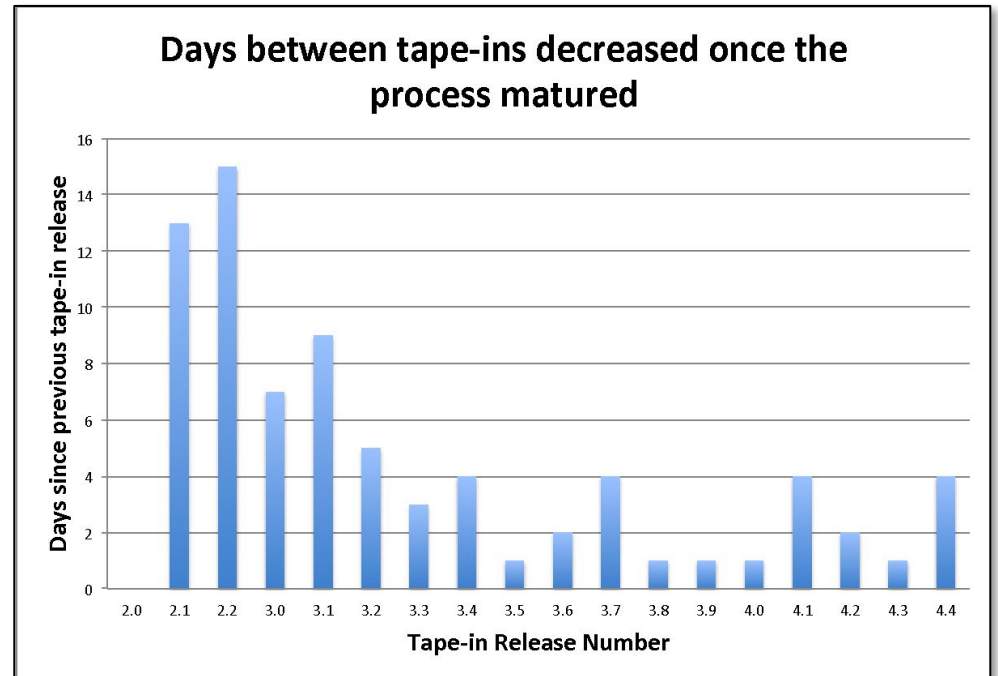
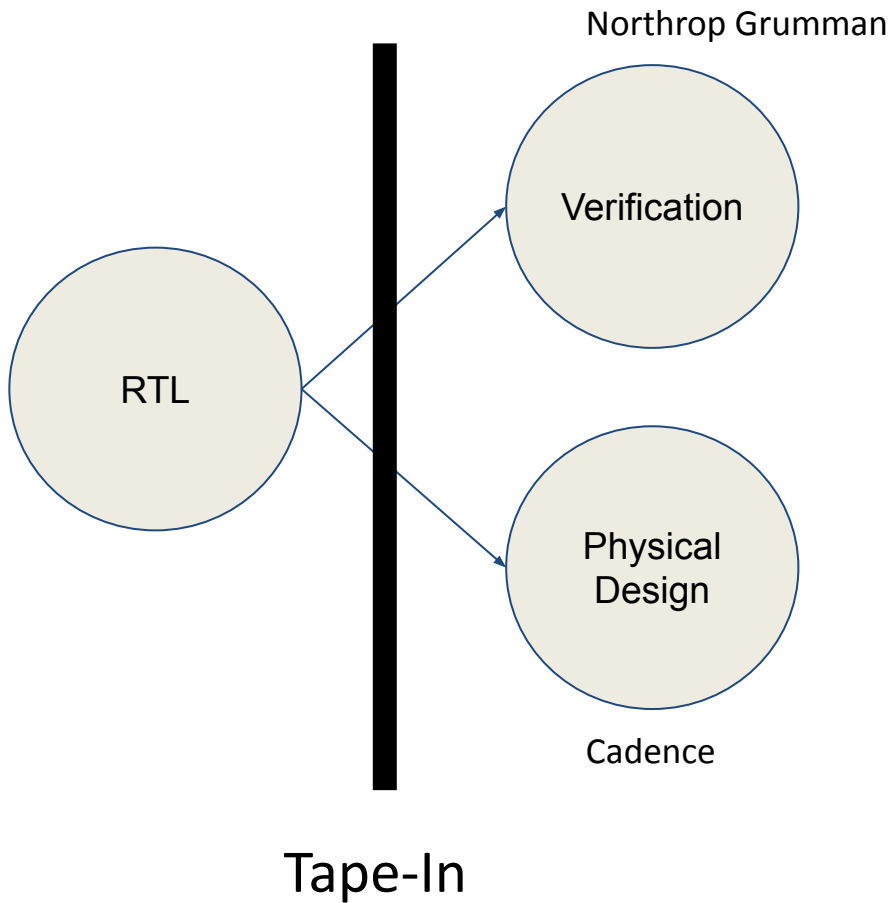
- 64-bit RISC-V processor
- 4-lane Hwacha vector unit
- DMA for DSP data movement acceleration
- 512 kB L2 cache
- 8 MB backing SRAM main memory
- 300 MHz DSP and core
- Custom IP integration (UART)
- JTAG backup controller
- Two verified AXI4 crossbars, 2x12 and 2x7
- Built-in debugging with 512 kB Logic Analyzer and 512 kB Pattern Generator
- 8-bit, 10 GHz time-interleaved SAR ADC with calibration
- Programmable digital tuner
- 136-tap programmable FIR filter
- 12-tap polyphase filter bank (PFB) with fixed coefficients
- 128-point FFT
- 5 stream-to-AXI4 memories (SAM) ranging in size from 64 kB to 256 kB
- Joint effort with Northrup Grumman Corporation (NGC) and Cadence Design Systems



Radar Chip Layout



Agile Methodology



Agile Methodology

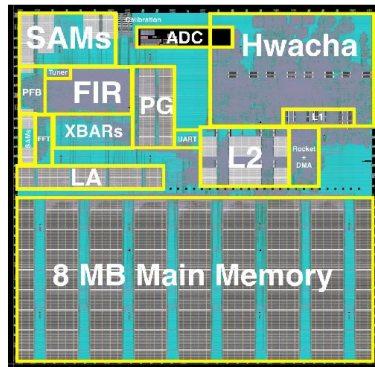
Signal Analysis SoC

~14,000 eng. hours

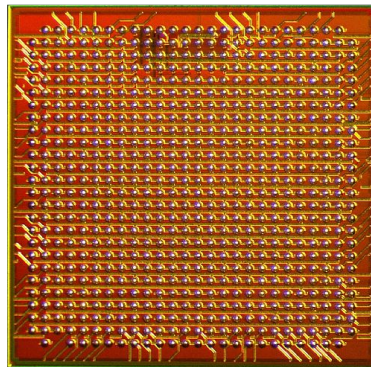


Sparse FFT

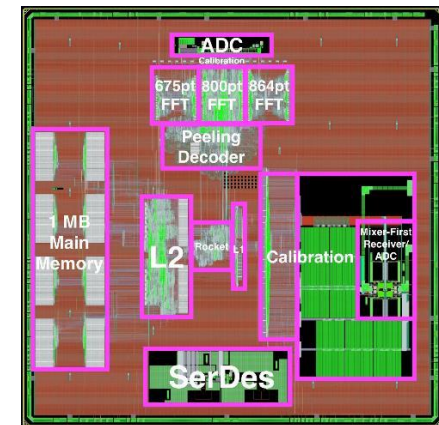
~3,000 eng. hours



Annotated Layout



Die Photo



Technology	16nm FinFET	
Die Area	5mm x 5mm (25mm ²)	
	General-Purpose Processor	Signal-Analysis Processor
Area	1.1 mm ² (gates) 9.2 mm ² (SRAM)	1.5 mm ² (gates) 0.8mm ² (SRAM)
Total SRAM Size	71 Mbits	14 Mbits
Voltage	0.56 V - 0.98 V	0.56 V - 0.98 V
Max Frequency	410 MHz	417 MHz
Power	349 mW @ 0.75V, 410 MHz	210 mW @ 0.75 V, 417 MHz
Max Throughput (Mspectra/s)	0.46 (vector) 0.004 (scalar) @ 410 MHz	13 @ 417 MHz
Efficiency	23.4 GFLOPS/W (0.56V, 191MHz) (DGEMM on vector accelerator)	19.2 TOPS/W (0.56V, 192MHz) (1 op = 8-bit add ~ 17-bit mul)

Summary and Lessons Learned

- Summary
 - Agile chip development is possible
 - We created a generalized DSP chip development methodology
 - We used this methodology to quickly realize multiple chips
- Lessons Learned
 - Stay flexible
 - Automate and version control
 - Design for reuse
 - Physical design was the bottleneck

Angie Wang

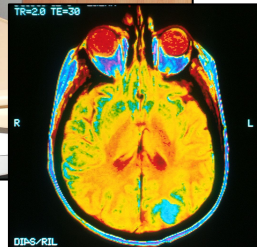
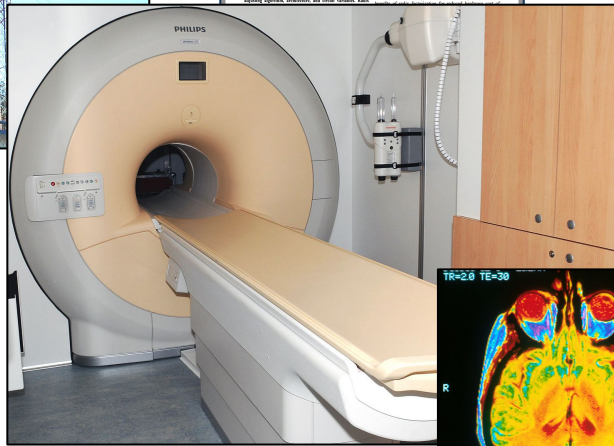
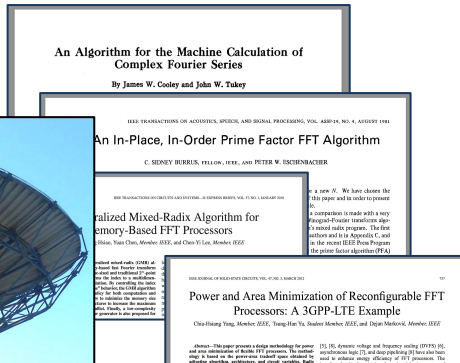
DSPTools for Building & Verifying Hardware FFT Generators

FFTs Are Everywhere!

- Hardware FFTs implemented countless times...

Core DSP in

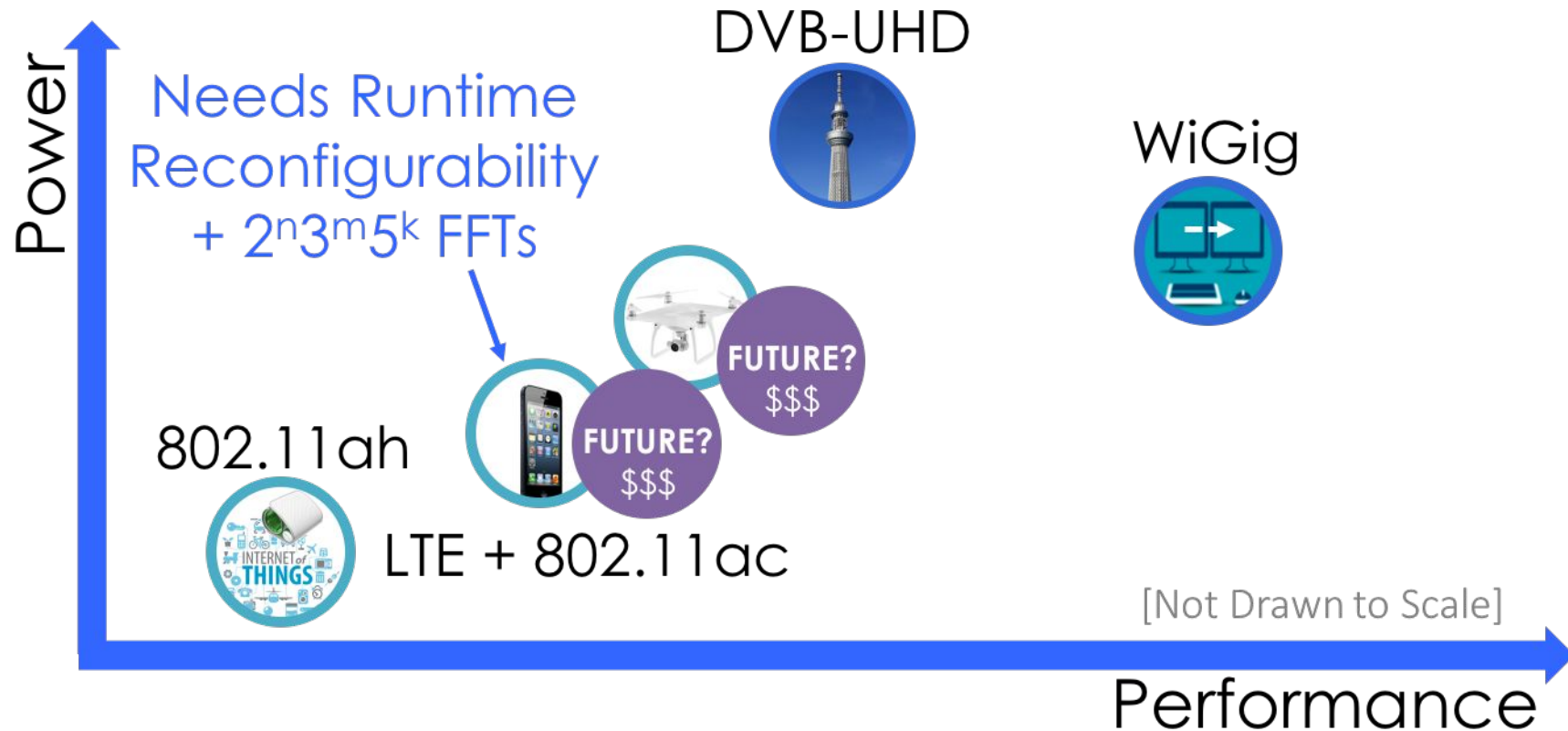
- Radio Astronomy
- Audio Signal Processing
- MRI
- ➔ Cognitive Radio / SDR **5G+**
 - LTE, Wi-Fi, Future Standards
 - Dynamic Spectrum Mgmt.
- Object Detection
- ... *You name it!*



[Wikimedia Commons]

Case Study: Wireless Communication

- How to generate a *hardware-optimized* building block for different standards?



➔ One-off designs (*runtime reconfigurable or otherwise*) not resource + time-efficient!

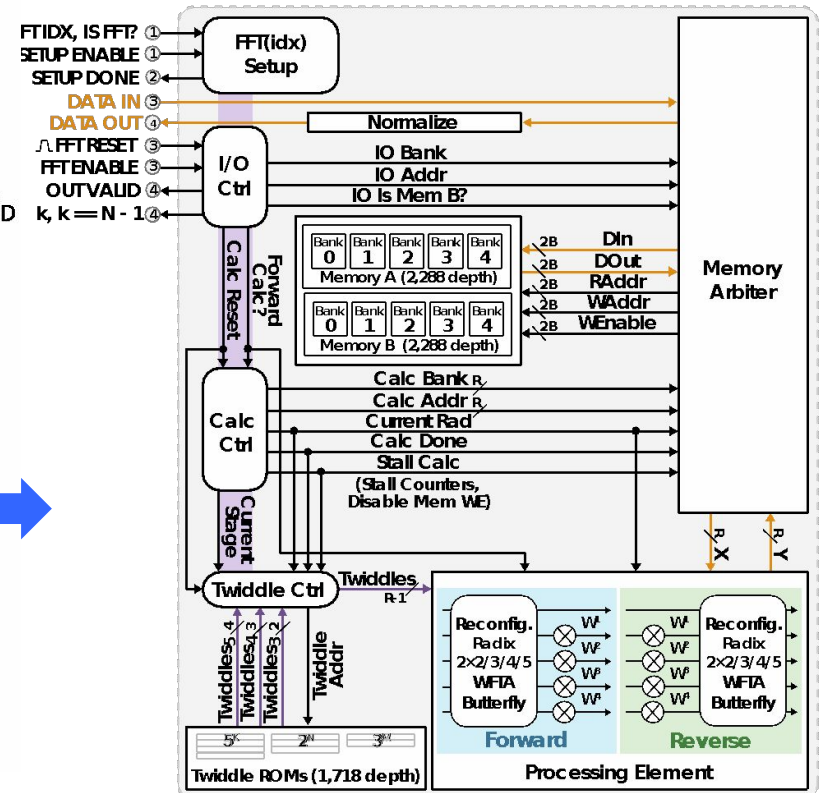
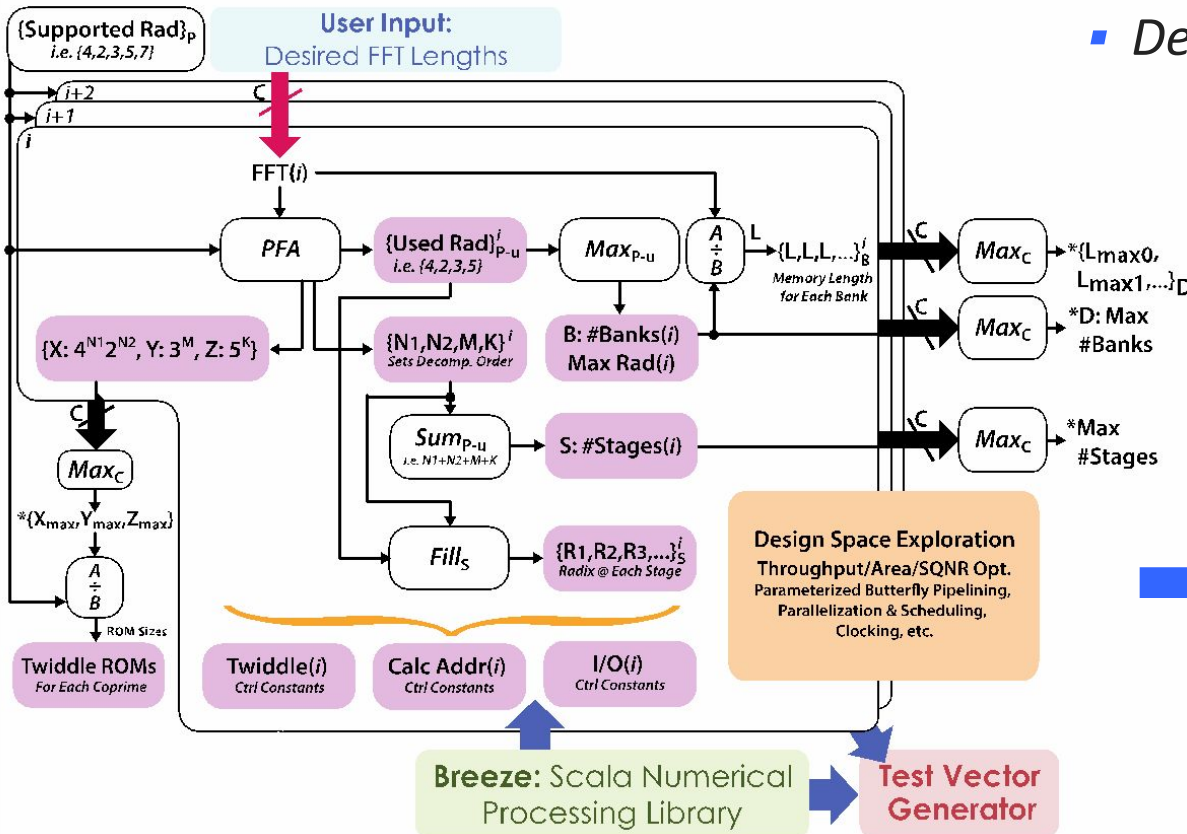
Mixed Radix, Runtime Reconfigurable FFT Generator

Scala "Firmware"

- Calculates constants for LUT generation
- Calculates optimized hardware params

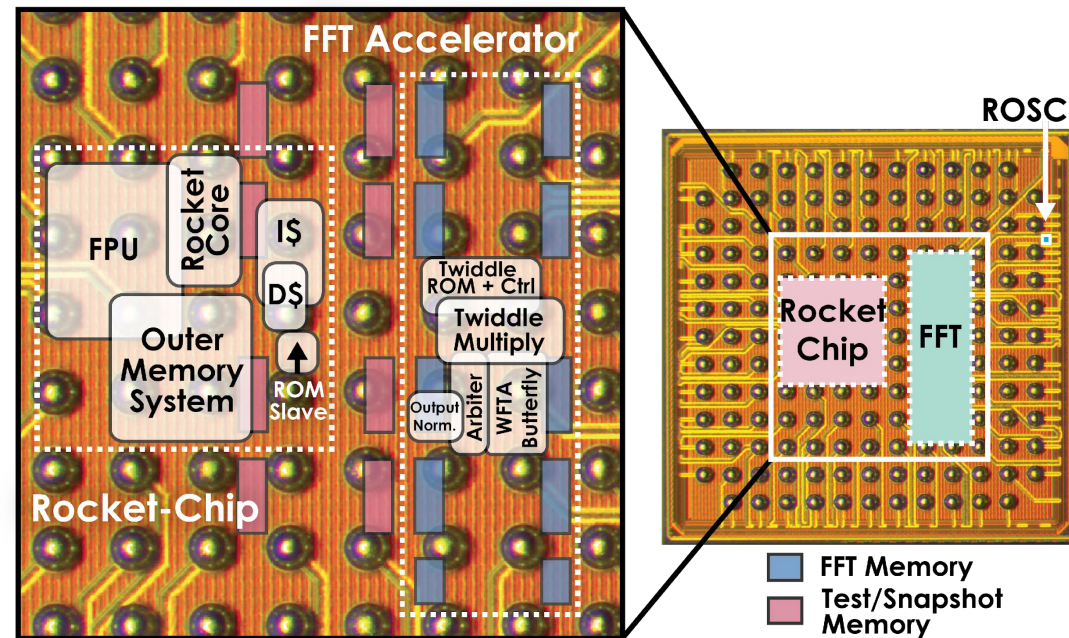
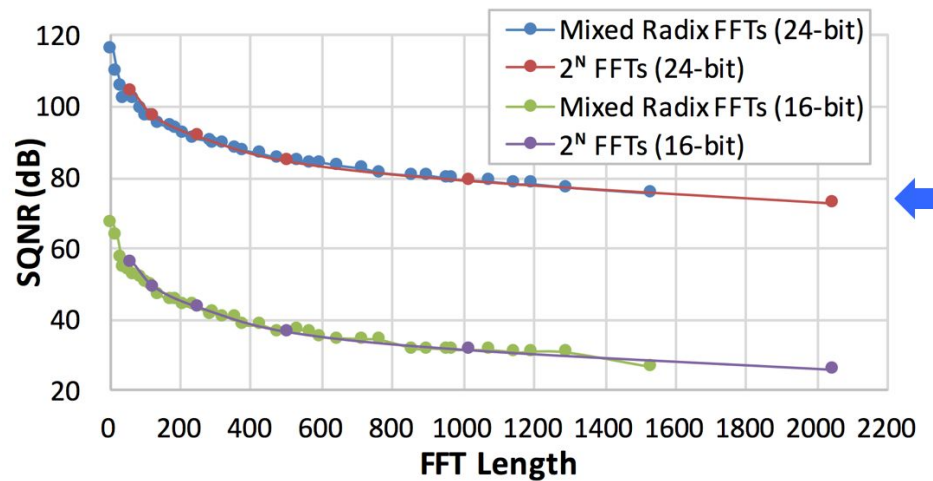
Chisel Hardware Template

- LUTs for reconfiguration + twiddles
- Configurable blocks controlling dataflow between IO, SRAMs, & PE(s)
- Design complexity mostly in ctrl logic



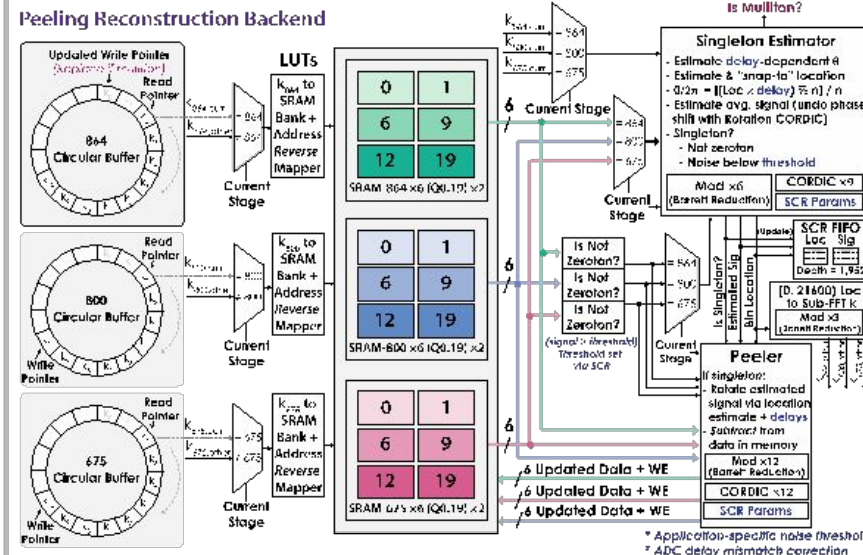
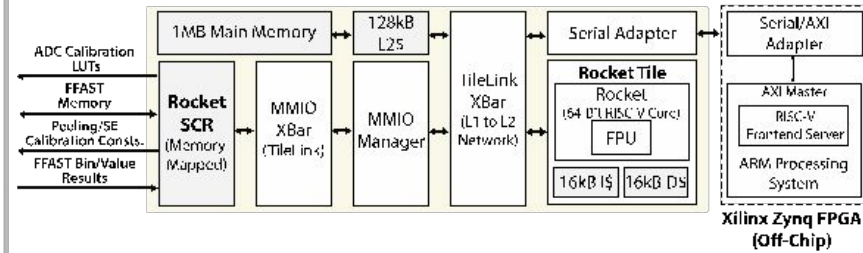
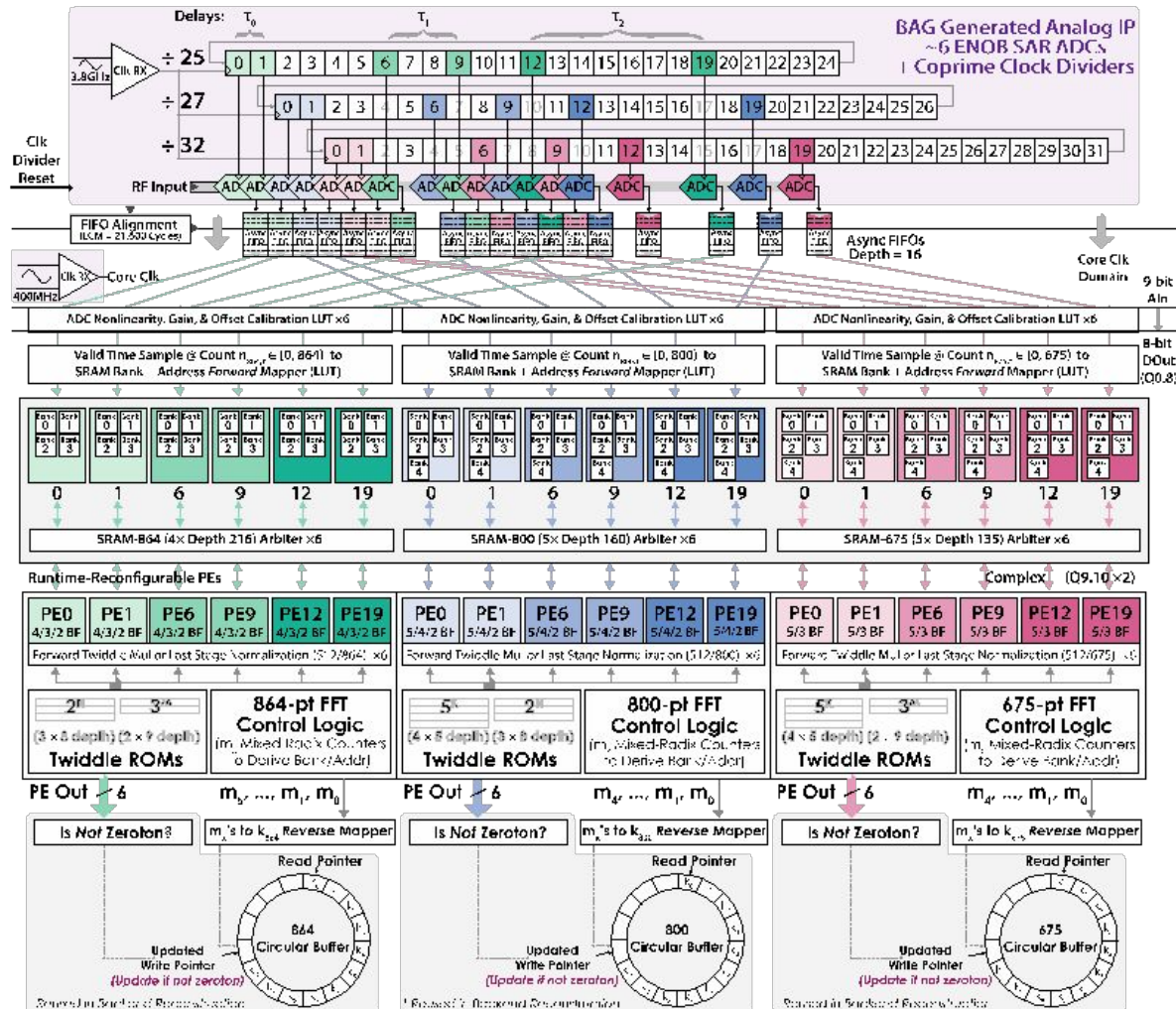
A 0.37-mm² LTE/Wi-Fi Compatible FFT Accelerator Integrated with a RISC-V Core in 16-nm FinFET

- Taped out in ~1 month from PDK delivery, with comparable performance to state-of-the-art
- Auto-generate C tests and run on Rocket-Chip



A Real-Time, 1.89-GHz Bandwidth, 175-kHz Resolution Sparse Spectral Analysis RISC-V SoC in 16-nm FinFET

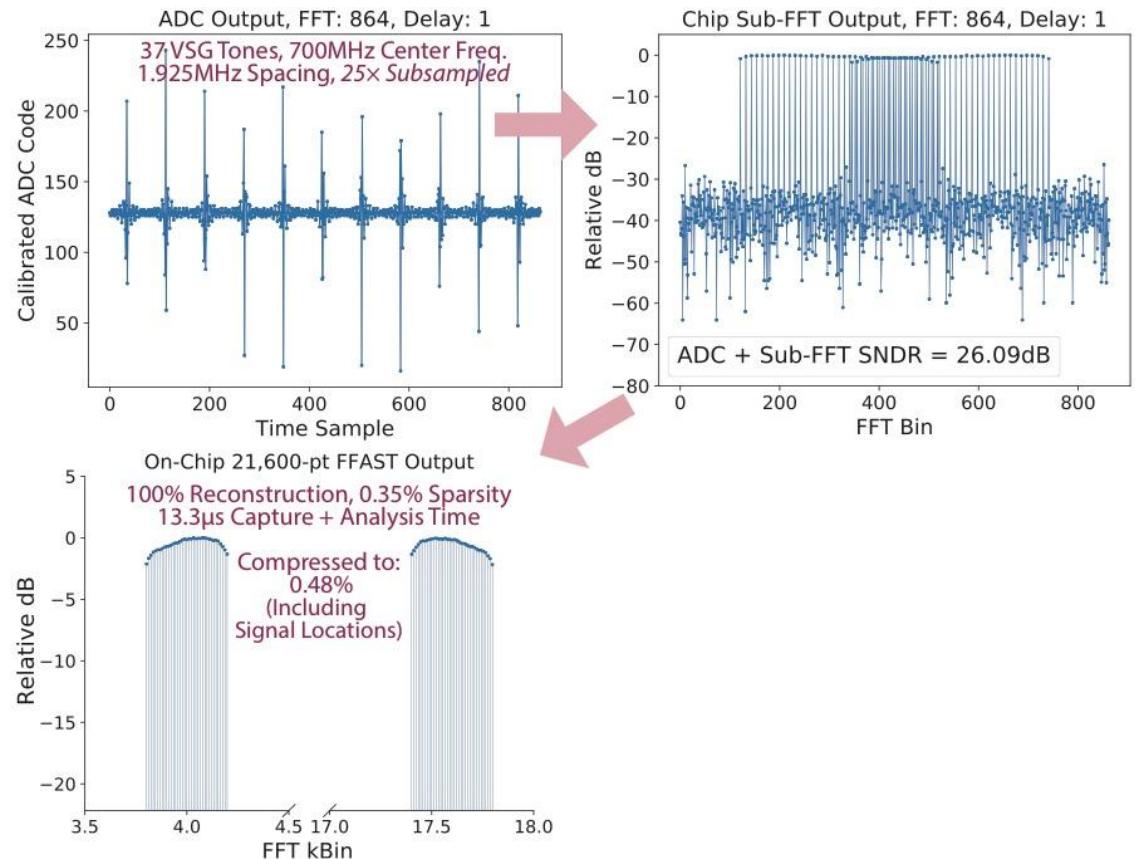
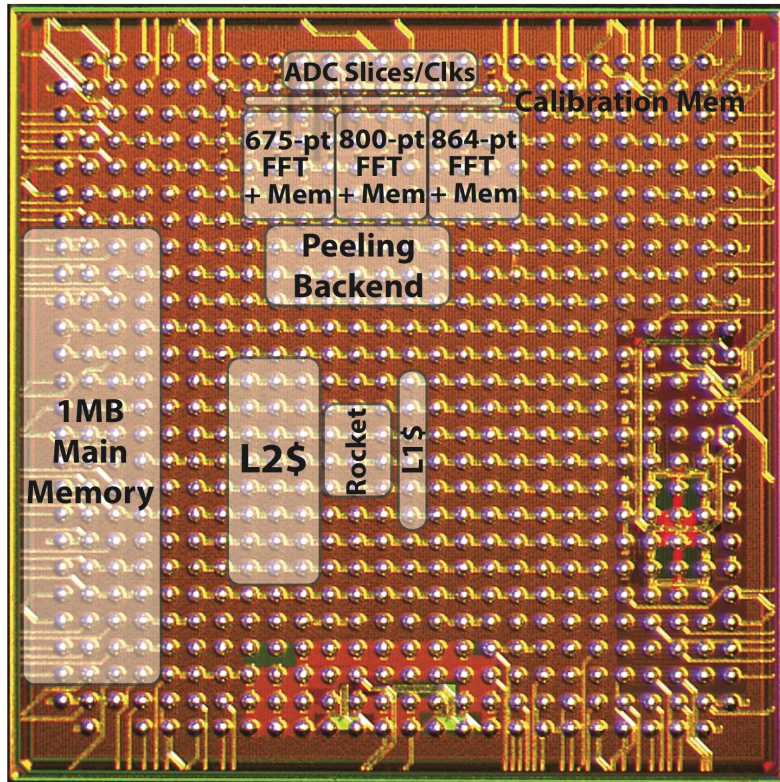
- ADCs modeled in Chisel, designed with BAG
- Mixed-radix FFTs + peeling reconstruction backend designed with Chisel



ADC Capture	Sub FFTs	Peeling CBs	Peeling 0, Stg 1	Peeling 0, Stg 2	Peeling 0, Stg 3	Peeling 1, Stg 1	Peeling 1, Stg 2
Rocket-Clp Windowing			Early Termination				
Any CB Empty or All CB Lengths Reached							

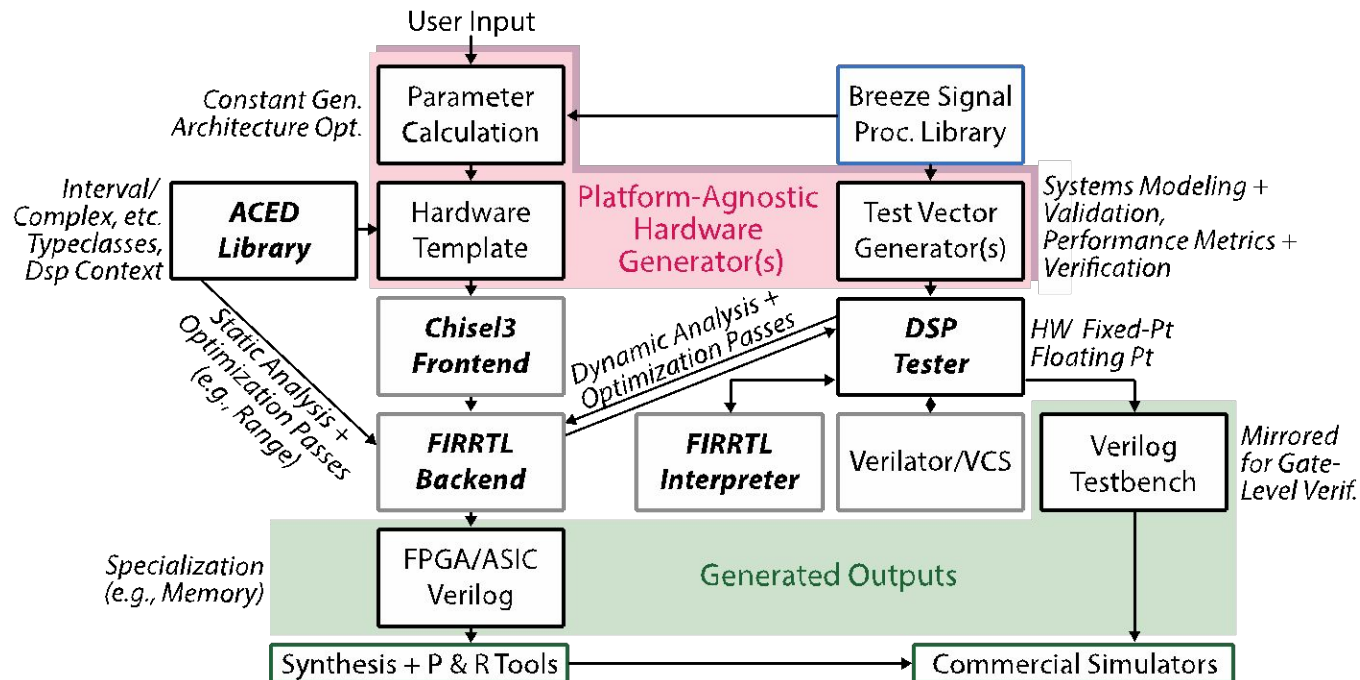
A Real-Time, 1.89-GHz Bandwidth, 175-kHz Resolution Sparse Spectral Analysis RISC-V SoC in 16-nm FinFET

- Chisel/BAG generators enabled the first automatically generated, fully-integrated, sparse spectral analysis SoC, completed in ~2 months



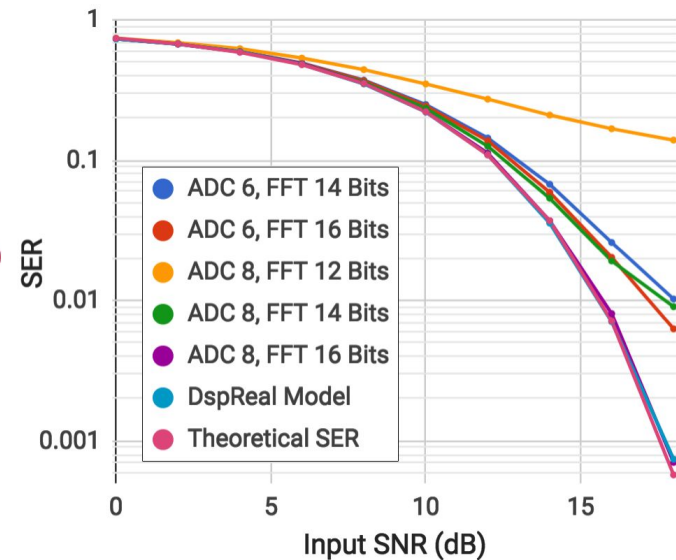
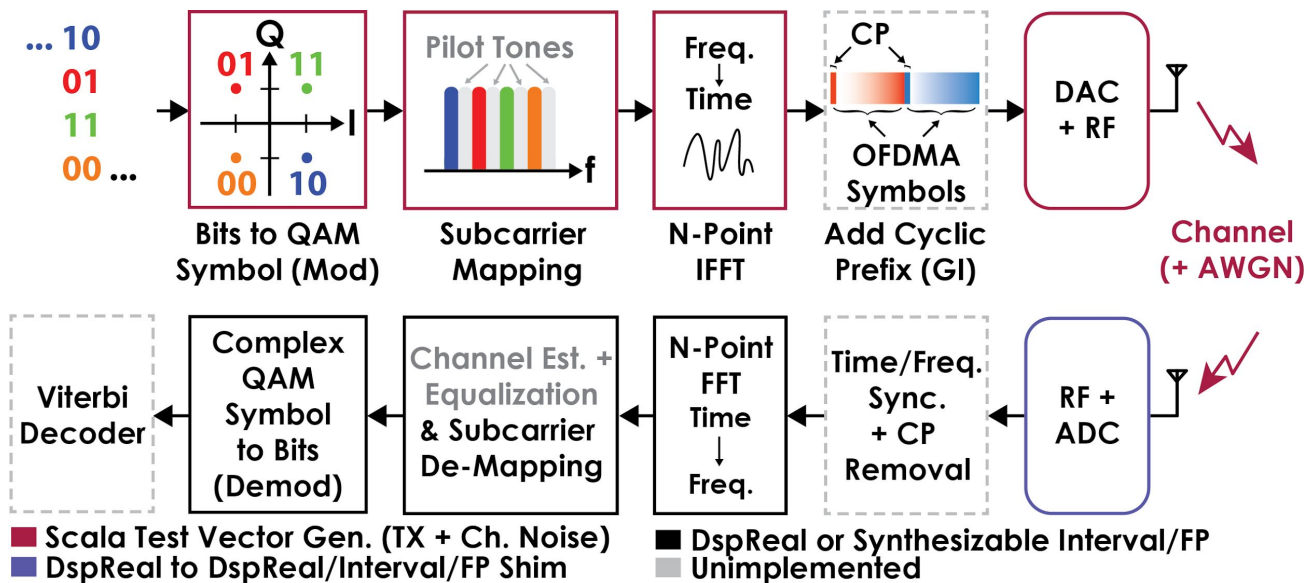
A Chisel Environment for DSP Generator Design

- Capture and propagate designer intent down the hardware abstraction hierarchy without redundant specification!
- Powerful meta-programming with **zero-cost** abstractions
 - Operator + data type parameterization
- **Unobtrusive** optimization and specialization
 - Automatic bitwidth reduction via static or simulation-based interval analysis
- **Unified**, yet portable modeling, validation, verification, and testing



Systems Modeling/Verification + Validation

- *DspReal* for verifying mathematical correctness/decoupling algorithmic errors from degraded performance due to quantization errors
 - Effective # of ADC bits
 - Fixed-point error propagation in the FFT, etc.
- Study system sensitivity to block performance via metrics like SER



- Use the same tests across all layers of the design stack to catch bugs

Summary

- The ACED DSP (aka DSPTools) library builds upon the Chisel ecosystem and vision.
- It operates at several *distinct* levels of abstraction.
 - High-level type-generic generators
 - Low-level bitwidth optimizations
- Tried-and-true techniques are brought immediately into the hands of the designer.
- Bitwidth optimization illustrates a powerful use case of FIRRTL's open-compiler framework in the context of writing DSP generators.
- Several chips have been fabricated using ACED